

## Short Biography

**Ivan J. LaHaie** received his BS degree in electrical engineering from Michigan State University in 1976, and his MS and Ph. D. degrees, also in electrical engineering, from the University of Michigan in 1977 and 1981, respectively. He joined the Environmental Research Institute of Michigan (ERIM) in 1980 and worked there for 30 years during its various incarnations as ERIM International, Veridian Systems, and General Dynamics Advanced Information Systems. He joined Integrity Applications Incorporated (later Centauri and KBR) in 2010, where he was a Senior Principal Scientist responsible for technical innovation, business development, and program management for the RF and Signature Technology (RFST) team in the Sensors and Analysis Sector until his retirement in 2021. Dr. LaHaie's interests lie in the application of electromagnetics, inverse scattering, and signal processing techniques to problems in radar cross-section (RCS) modeling, analysis, and measurements, synthetic aperture radar (SAR) systems and phenomenology, and unconventional RF and optical imaging. He is a nationally-recognized authority in the development of techniques for RCS measurement error mitigation, near field-to-far field RCS transformations, low observable (LO) signature diagnostics, and RCS uncertainty analysis, and has participated in several government advisory and technical evaluation panels.

Dr. LaHaie is a life fellow of the Institute of Electrical and Electronics Engineers (IEEE) and a fellow of the Antenna Measurement Techniques Association (AMTA), and a member Sigma Xi. In 1991, he received the IEEE Aerospace and Electronic Systems Society Radar Systems Panel Award (now the Fred Nathanson Memorial Radar Award) for his contributions to synthetic aperture systems and electromagnetic modeling. The award is given annually to the nation's leading radar engineer under 40 years of age. He received the AMTA Distinguished Achievement award in 2004 for his pioneering work in the development of automated radar signature imaging technology, RCS measurement technology and standards, the design and evaluation of electromagnetic interference and error source mitigation techniques, and for his contributions to the field of radar signature target support interaction modeling.